

#5

USPTO  
09/977787  
10/15/01

FORM PTO-1449 (SUBSTITUTE)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		Attorney Docket No.: W&B-INF-860 Appl. No.
INFORMATION DISCLOSURE STATEMENT BY APPLICANT (37 CFR 1.98(b))		Applicant UDO HARTMANN
		Filing Date October 15, 2001 Group Art Unit 2133

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
<i>JY</i>	A	6,195,771 B1	02/01	Tanabe et al.			
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES	TRANSL. NO
<i>JY</i>	J	EP 0 828 257 A2	03/98	Europe	—	—		
	K							
	L							
	M							
	N							

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

<i>JY</i>		Tadahiko Sugibayashi et al.: "A Distributive Serial Multi-Bit Parallel Test Scheme for Large Capacity DRAMs", IEICE Trans. Electron., Vol. E77-C, No. 8, August 1994, pp. 1323-1327;

EXAMINER <i>John Truett</i>	DATE CONSIDERED <i>3/9/04</i>
EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	